

Model 5710

DC Power Supply Test System



Engineering Characterization & Design Verification Functional Test

Features

- Tektronix MDO-Series Mixed Signal Oscilloscope
- Unlimited voltage, current & timing measurements relative to digital signals.
- Library of design verification test routines reduces program development time
- Configuration flexibility

Applications

The Model 5710 is designed to yield comprehensive test data on a wide range of AC-DC and DC-DC power supplies with a minimum of programming effort. Such characterization testing is typically done in an engineering design-verification laboratory where the user's own designs or vendor prototypes are evaluated. This type of extensive testing is also often required for high-reliability power supplies used in medical, telecommunication, space and avionic applications.

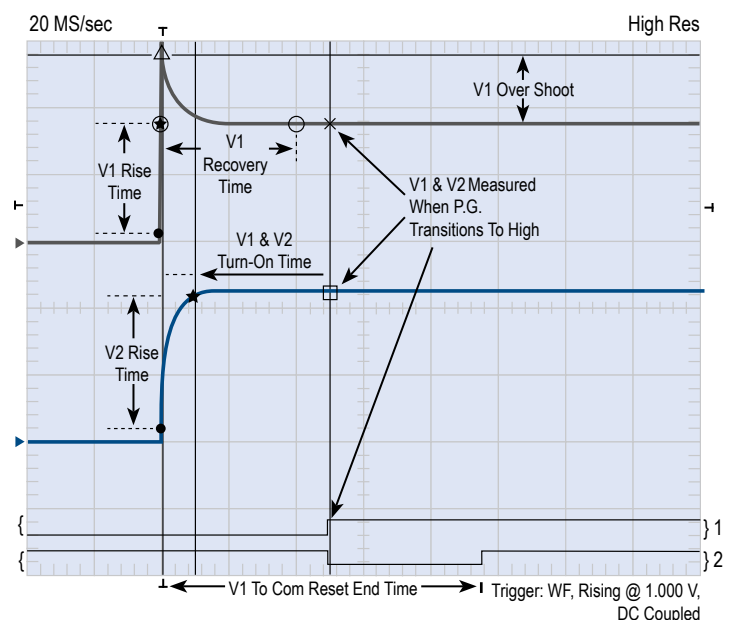
PowerScope High-Speed Digitizer

The Model 5710 embeds a mixed-signal Tektronix MDO-Series oscilloscope as the system digitizer with three channels each of which can sample up to a 2.5 GSPS rate. The digitizing function is further extended by paring two of the channels with a 16-channel multiplexer thus allowing automated selection and measurement of different measurement points. When more than 17 inputs are required, multiple 15-input extension chassis may be added to the system further increasing the multiplexing capability.

With a full 100 MHz of bandwidth, the primary multiplexing channel as well as the third fixed input channel precisely captures and digitizes fast moving signals. The second multiplexing channel supports 10 MHz bandwidth making it ideal for measuring DC and other slower moving signals. In mixed signal applications, a 16-input digital input captures digital signals along with analog measurements. All of the above measurements are synchronously captured, which provides complex analog-analog or analog-digital timing analysis. Finally, a 10 Mega-sample memory depth easily captures non-repetitive transients as well as digital states even when they occur with a relatively long separation from the trigger event.



Model 5710 in a 3-bay cabinet



Unlimited cursors and markers identify the exact point where the measurement is to be taken.

Design Verification Test Routines

To complement the powerful digital measurement system, a special suite of test routines are provided to determine power supply performance characteristics far beyond that available on a basic production tester. For instance, more than 20 different measurements can be extracted from each waveform capture and channel-to-channel measurements are all straight forward to execute. One example of this capability is sweep tests where one parameter, such as efficiency, is plotted across the full range of another parameter like output voltage or power. This test can now be programmed and executed in minutes rather than the hours and days required by previous generation test systems.

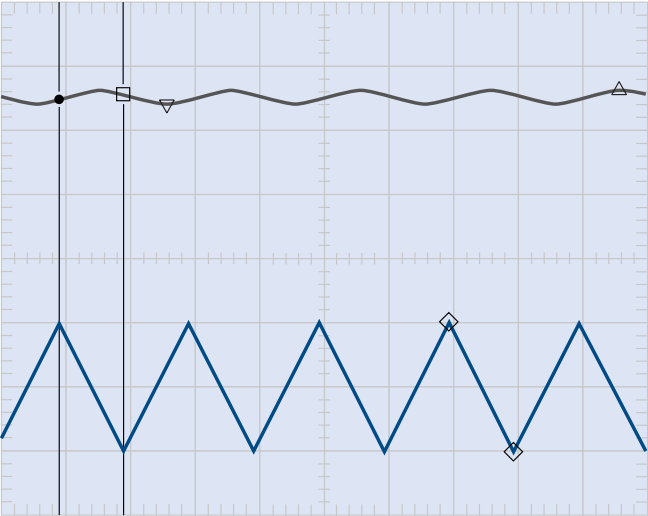
MODEL 5710 EMPOWER TEST CAPABILITY			
General Tests	Output Accuracy Output Adjustment Output Trim RMS Noise/Ripple Operator Data Entry, Test, Visual Acceptance & Instructions Power Fail Signal Power Good Signal P/ S ON Signal Operator Waveform Inspection Multi-Measure Monotonicity Shock/ Shake Test	Timing Tests	Rise-Time Fall Time Turn-On Time Turn-On Sequence (load-to-load timing) Turn-Off Time Turn-Off Sequence (load-to-load timing) Hold-Up Time Transient Recovery Time Overshoot Width Undershoot Width Pulsewidth as Time Pulsewidth as Frequency Multiple-Timing (Unlimited-Cursors)
	Regulation Tests Load Regulation Cross-Load Regulation Voltage Regulation Current Regulation Power Regulation	Control	Single Digital Control BYTE/WORD Digital Control OVP (OverVoltage) Driver OTP (OverTemperature) Driver Start/ Stop/ Pass/ Fail/ Busy/ Ready Controls 8 Measurement Channels Control for Vout & ID Outputs
		Output Measurement	Voltage Current Power Digital State DC Positive Peak DC Negative Peak Voltage & Current Waveform Capture and Analysis Frequency Mean RMS AC Coupled RMS DC Coupled Peak Max Peak Min Peak-Peak Peak Absolute Time at Event Timing as Frequency Measurement at Event
	Protection Tests Over-Current Ramp Protection High Accuracy Over-Current Slew Protection Over-Voltage Protection (no scope required) Under-Voltage Protection High Accuracy Over-Power Slew Protection Over-Power Protection Short-Circuit Protection (up to 100A) Over-Temperature (via relay control)		
Dynamic Tests	Single Load Transient Synchronized Multi-Output Load Transient Worst-Case Dynamic Transient (Frequency & Duty Cycle) Overshoot Undershoot Settle/ Recovery Voltage Settle/ Recovery Time		
		Real Time (Manual Control)	Interactive Real-Time Hardware Control Step-by-step Interactive Test Program Break Point for Fixture & UUT Debug

Test Report Examples

Triangular Current Waveform Measurements

Vout Max	4.700 V	5.155 V	5.300 V	Pass
Vout Min	4.700 V	4.747 V	5.300 V	Pass
Iout Max	2.950 A	3.030 A	3.050 A	Pass
Iout Min	950.000 mA	1.016 A	1.050 A	Pass
Vout @ 1st Iout Max	4.700 V	4.851 V	5.300 V	Pass
Vout @ 1st Iout Min	4.700 V	5.062 V	5.300 V	Pass
Iout Frequency	495.000 Hz	497.512 Hz	505.000 Hz	Pass

50 KS/sec



1.000 mS/div Trigger: System Trigger

WF1, (Current): 1 A/div, 0.0A @ -4 Div. WF2, (Voltage): 2 V/div, 0.0V @ 0 Div.

Vout Max: Max = Δ WF2: Voltage @ 9.560 mS, 5.155 V

Vout Min: Min = ▽ WF2: Voltage @ 2.560 mS, 4.747 V

Iout Max: Max = ◇ WF1: Current @ 6.940 mS 3.030 A

Iout Min: Min = ◇ WF1: Current @ 7.940 mS 1.016 A

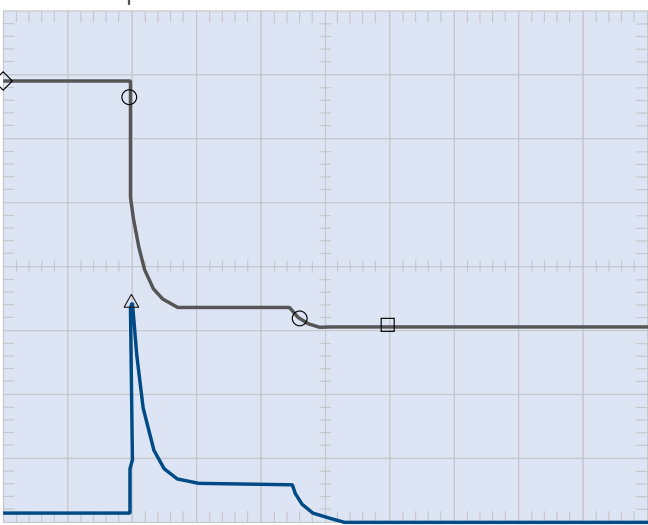
Vout @ 1st Iout Max: Min = ● WF1: Current @ 900.000 uS, 4.851 V

Vout @ 1st Iout Min: Max = □ WF1: Current @ 1.900 mS, 5.062 V

Short-Circuit Test

UUT Short-Circuit Response Time	0.000 S	2.592 mS	4.000 mS	Pass
Max Short-Circuit Current	3.340 A	69.034 A	75.000 A	Pass
Vout Before Short-Circuit	18.525 V	19.348 V	20.475 V	Pass
Vout 4mS After Short Circuit	0.000 V	100.637 mV	1.000 V	Pass

5MS/sec



1.000 mS/div Trigger: WF 1, Falling @ 16.500 V. DC Coupled

WF1, Chn 001, 5V/div. WF2, Chn 002, 20 A/div.

UUT Short-Circuit Response Time: Start = ○ WF1: Chn 001 @ 1.996 mS, 18.412 V:

Stop = ○ WF1: Chn 001 @ 4.589 mS, 0.971 V

Max Short-Circuit Current: Max = Δ WF2: Chn 002 @ 2.020 mS, 69.034 A

Vout Before Short-Circuit: Mean = ◇ WF1: Chn 001 @ 0.000 S, 19.348 V

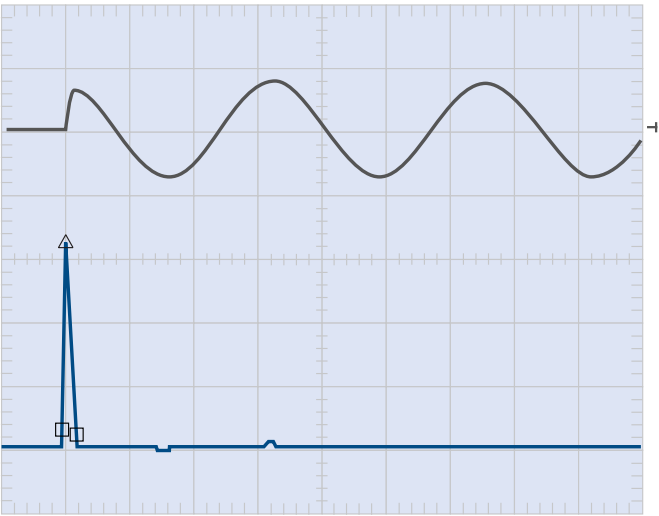
Vout 4mS After Short-Circuit: Event = □ WF1: Chn 001 @ 6.000 mS, 100.637 mV

Inrush Waveform Measurement

Inrush Current	40.000 A	65.071 A	76.000 A	Pass
Inrush Current Width	500.000 uS	741.000 uS	2.000 mS	Pass
Vin	262.000 V	263.682 V	266.000 V	Pass
Vin Frequency	59.000 Hz	60.588 Hz	61.000 Hz	Pass

1MS/sec

High Res



5.000 mS/div Trigger: WF 3. Rising @ 30.012 V. DC Coupled

WF1, Chn 003, 20A/div. WF3, Fixed, 500 V/div.

Inrush Current: Max = Δ WF1: Chn 005 @ 5.201 mS, 65.071 A

Inrush Current Width: Start = □ WF1: Chn 003 @ 4.925 mS, 6.762 A: Stop = □

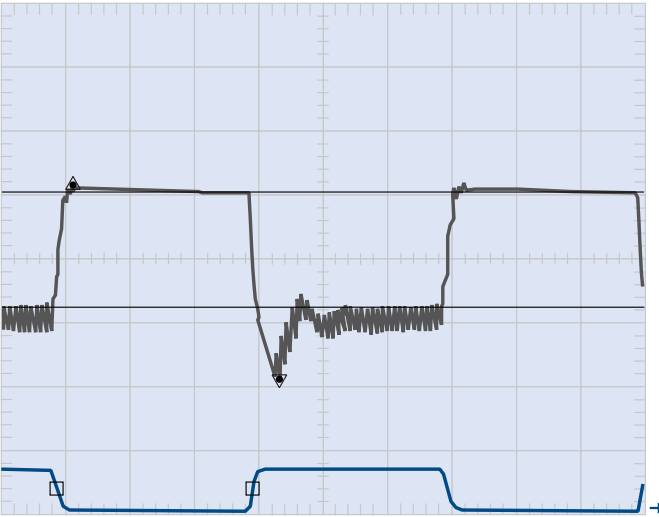
WF1: Chn 003 @ 5.666 mS, 5.505 A

Dynamic Test

Vout Max	0.000 V	239.784 mV	500.000 mV	Pass
Vout High	0.000 V	209.241 mV	500.000 mV	Pass
Vout Min	0.000 V	-371.088 mV	-500.000 mV	Pass
Vout Low	0.000 V	-151.174 mV	-500.000 mV	Pass
Vout Overshoot	0.000 V	31.410 mV	500.000 mV	Pass
Vout Undershoot	0.000 V	145.136 mV	500.000 mV	Pass
Iout Pulse Width	585.000 uS	603.800 uS	615.000 uS	Pass
Iout Frequency	1.650 KHz	1.656 KHz	1.690 KHz	Pass

5 MS/sec

High Res



200.000 uS/div Trigger: WF2, Falling @ 500.000 mA DC Coupled

WF1, Chn 001, 200 mV/div, AC. WF2, Chn 002, 5 A/div.

Vout Max: Max = Δ WF1: Chn 001 @ 222.400 uS, 239.784 mV

Vout High: High = WF1: Chn 001 @ 0.000 S, 209.241 mV

Vout Min: Min = ▽ WF1: Chn 001 @ 866.800 uS, -371.088 mV

Vout Low: Low = WF1: Chn 001 @ 0.000 S, -151.174 mV

Vout Overshoot: Max = ● WF1: Chn 001 @ 222.400 uS, 239.784 mV

Vout Undershoot Min = ● WF1: Chn 001 @ 866.800 uS, -371.088 mV

Iout Pulse Width: Start = □ WF2: Chn 002 @ 184.000 uS, 1.840 A: Stop = □ WF2: Chn

002 @ 787.800 uS, 1.848 A

